


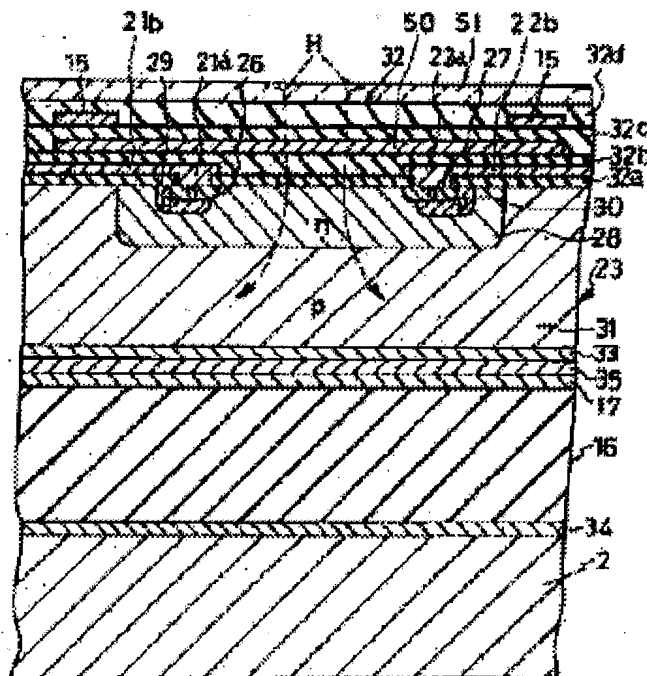


CURRENT DETECTOR PROVIDED WITH HALL ELEMENT**Publication number:** JP2001230467**Publication date:** 2001-08-24**Inventor:** OTSUKA KOJI**Applicant:** SANKEN ELECTRIC CO LTD**Classification:****- international:** G01R15/20; H01L43/06; G01R15/14; H01L43/06;
(IPC1-7): H01L43/06**- European:** G01R15/20B; H01L43/06B**Application number:** JP20000249472 20000821**Priority number(s):** JP20000249472 20000821; JP19990350064 19991209**Also published as:** EP1107327 (A2)
 US6812687 (B1)
 EP1107327 (A3)[Report a data error here](#)**Abstract of JP2001230467****PROBLEM TO BE SOLVED:** To detect a current with accuracy by using a Hall element.**SOLUTION:** On an insulation film 32 formed on the surface of a semiconductor substrate 23 which constitutes the Hall element 1, a conductor layer 15 is formed as a current path. The conductor layer 15 is so disposed as to surround a main operating region of the Hall element 1. Between the conductor layer 15 and the semiconductor substrate 23, a Mo-made shield layer 50 is disposed to prevent dielectric noise.

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Family list5 family members for: **JP2001230467**

Derived from 3 applications

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- 1 Semiconductor current detector of improved noise immunity**
Inventor: OHTSUKA KOJI (JP) **Applicant:** SANKEN ELECTRIC CO LTD (JP)
EC: G01R15/20B; H01L43/06B **IPC:** G01R15/20; H01L43/06; G01R15/14 (+2)
Publication info: **EP1107327 A2** - 2001-06-13
EP1107327 A3 - 2004-12-29
- 2 CURRENT DETECTOR PROVIDED WITH HALL ELEMENT**
Inventor: OHTSUKA KOJI **Applicant:** SANKEN ELECTRIC CO LTD
EC: G01R15/20B; H01L43/06B **IPC:** G01R15/20; H01L43/06; G01R15/14 (+2)
Publication info: **JP3852554B2 B2** - 2006-11-29
JP2001230467 A - 2001-08-24
- 3 Semiconductor current detector of improved noise immunity**
Inventor: OHTSUKA KOJI (JP) **Applicant:** SANKEN ELECTRIC CO LTD (US)
EC: G01R15/20B; H01L43/06B **IPC:** G01R15/20; H01L43/06; G01R15/14 (+2)
Publication info: **US6812687 B1** - 2004-11-02

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